

(a)



Figure 1. Si shadow masks (cross-sectional view): (a) 200 µm mask, (b) 500 µm mask; (c) Simplified sketch of MBE growth chamber displaying orientation of shadow mask in contact with substrate (cross-sectional view) during inplane GPM synthesis process (reproduced from)³; (d) 2D orientation of substrate with respect to the elemental cells during in-plane GPM synthesis process (top view).



Figure 2. Nano-FTIR spectra obtained by scattering-type scanning near-field optical microscopy (s-SNOM) using a mid-IR nano-FTIR module (~650 cm⁻¹ – 1400 cm⁻¹), illustrating the GPMs are localizing and enhancing different infrared light wavelengths: (a) GPM synthesized with 200 μ m mask. Wavelength-dependent light enhancement is observed and indicated by the gradient in wavenumber (~650 cm⁻¹ to 900 cm⁻¹) with respect to the GPM width of ~13 μ m. (b) GPM synthesized with 500 μ m mask. Wavelength-dependent light enhancement is observed and indicated by the gradient in wavenumber (~650 cm⁻¹ to 1450 cm⁻¹) with respect to the GPM width of ~30 μ m.